Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/690,321	LIM ET AL.	
Examiner	Art Unit	
Suk Jin Kang	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
370	236	5/30/2007	SJK	
370	236.2	5/30/2007	SJK	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH S)
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	5/30/2007	SJK
Inventor name and Assignee search in PALM ExPO and EAST	5/30/2007	sJK
Consulted with Rafael Perez-Gutierrez (SPE)	5/30/2007	SJK
Consulted with Chau Nguyen (SPE)	5/30/2007	SJK
(370/236, 229, 230, 231, 235, 236, 236.2, 395.42, 469.ccls.) or (709/240.ccls.)	5/30/2007	SJK
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